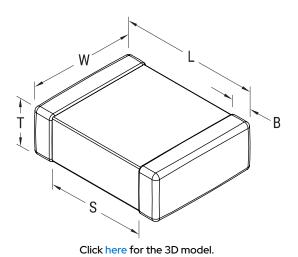


C0402C162K3TACTU

Aliases (C0402C162K3TAC7867)

SMD Comm X8G HT150C, Ceramic, 1,600 pF, 10%, 25 VDC, X8G, SMD, MLCC, High Temperature, Ultra-Stable, 0402, 0.3 mm



General Information	
Series	SMD Comm X8G HT150C
Style	SMD Chip
Description	SMD, MLCC, High Temperature, Ultra-Stable
Features	High Temperature, Ultra-Stable
RoHS	Yes
Termination	Tin
Marking	No
AEC-Q200	No
Typical Component Weight	1.06 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	0402
L	1mm +/-0.05mm
W	0.5mm +/-0.05mm
Т	0.5mm +/-0.05mm
S	0.3mm MIN
В	0.3mm +/-0.1mm

W	0.5mm +/-0.05mm	Tolerance	10%
Т	0.5mm +/-0.05mm	Voltage DC	25 VDC
S	0.3mm MIN	Dielectric Withstanding Voltage	62.5 VDC
В	0.3mm +/-0.1mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
Packaging Specifications		Capacitance Change with	30 ppm/C, 1kHz 1.0Vrms
Packaging	T&R, 180mm, Paper Tape	Reference to +25°C and 0 VDC Applied (TCC)	., ,
Packaging Quantity 10000	Dissipation Factor	0.1% 1 kHz 1.0Vrms	
		Aging Rate	0% Loss/Decade Hour: Referee

Specifications	
Capacitance	1,600 pF
Measurement Condition	1 kHz 1.0Vrms
Tolerance	10%
Voltage DC	25 VDC
Dielectric Withstanding Voltage	62.5 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1kHz 1.0Vrms
Dissipation Factor	0.1% 1 kHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

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